

Notice of References Cited

Application/Control No.

09/981,865

Applicant(s)/Patent Under
Reexamination
HOFF ET AL.

Examiner

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Art Unit

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	C	US-6,690,399 B1	02-2004	Carlson et al.	345/771
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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